

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	40			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 \text{ V}$	0.00084			
I _D (A)	409			
Configuration	Single			
Qg (nC)	250			

FEATURES

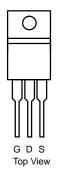
- Trench Power MOSFET
- 100 % R_g and UIS Tested

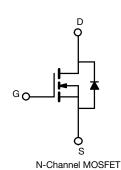
APPLICATIONS

- Synchronous Rectification
- Power Supplies









ABSOLUTE MAXIMUM RATING	S (T _C = 25 °C, unless	s otherwise noted	(k	
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-source voltage		V _{DS}	40	V
Gate-source voltage		V_{GS}	± 20	
Continuous drain current ^a	T _C = 25 °C	1	409	
	T _C = 125 °C	I _D	320	
Continuous source current (diode conduction) ^a		Is	409	Α
Pulsed drain current ^b		I _{DM}	600	
Single pulse avalanche current	L = 0.1 mH	I _{AS}	100	
Single pulse avalanche energy	L = 0.1 MH	E _{AS}	500	mJ
Maximum power dissipation ^b	T _C = 25 °C	D	375	14/
	T _C = 125 °C	- P _D	125	W
Operating junction and storage temperature	range	T _J , T _{stg}	-55 to +175	°C

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-ambient PC	CB mount c	R_{thJA}	40	°C/W
Junction-to-case (drain)		R_{thJC}	0.4	C/VV

Notes

- a. Based on T = $25 \, ^{\circ}$ C.
- b. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%$
- c. When mounted on 1" square PCB (FR4 material)

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PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-source breakdown voltage	V_{DS}	V _{GS} =	= 0 V, I _D = 250 μA	40	-	-	V	
Gate-source threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2.5	3.0	3.5	V	
Gate-source leakage	I _{GSS}	V _{DS} =	0 V, V _{GS} = ± 20 V	-	-	± 100	nA	
		$V_{GS} = 0 V$	V _{DS} = 40 V	=	-	1		
Zero gate voltage drain current	I _{DSS}	V _{GS} = 0 V	V _{DS} = 40 V, T _J = 125 °C	=	-	50	μA	
		V _{GS} = 0 V	V _{DS} = 40 V, T _J = 175 °C	-	-	300	μΑ	
On-state drain current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 \text{ V}$	100	-	-	Α	
		$\begin{array}{c ccccccccccccccccccccccccccccccccccc$						
Drain-source on-state resistance ^a	R _{DS(on)}	V _{GS} = 10 V	I _D = 35 A, T _J = 125 °C	-	0.00140	-		
		V _{GS} = 10 V	I _D = 35 A, T _J = 175 °C	-	0.00164	-		
Forward transconductance b	9 _{fs}	V_{DS}	= 15 V, I _D = 30 A	-	196	-	S	
Dynamic ^b							•	
Input capacitance	C _{iss}			-	11 938	15 525		
Output capacitance	C _{oss}	$V_{GS} = 0 V$	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	-	11 163	14 520	pF	
Reverse transfer capacitance	C _{rss}			-	282	370		
Total gate charge ^c	Qg			-	158	250		
Gate-source charge c	Q_{gs}	V _{GS} = 10 V	$V_{DS} = 20 \text{ V}, I_{D} = 100 \text{ A}$	-	44	-	nC	
Gate-drain charge ^c	Q _{gd}			-	22	-		
Gate resistance	R_g		f = 1 MHz	2.70	5.44	8.20	Ω	
Turn-on delay time c	t _{d(on)}			-	16	25		
Rise time ^c	t _r	V _{DD} =	= 20 V, $R_L = 0.2 \Omega$	-	10	17	ns	
Turn-off delay time ^c	t _{d(off)}	$I_D \cong 100 A$	V_{GEN} = 10 V, R_g = 1 Ω	-	103	160		
Fall time ^c	t _f	1		-	61	95		
Source-Drain Diode Ratings and Chara	cteristics ^b							
Pulsed current ^a	I _{SM}			-	-	260	Α	
Forward voltage	V _{SD}	I _F = 60 A, V _{GS} = 0 V		-	0.81	1.5	V	
Body diode reverse recovery time	t _{rr}			-	165	350	ns	
Body diode reverse recovery charge	Q _{rr}	l _F = 30 A, di/dt = 100 A/μs		-	530	1100	nC	
Reverse recovery fall time	t _a			-	66	-		
Reverse recovery rise time	t _b	1		-	99	-	ns	
Body diode peak reverse recovery current	I _{RM(REC)}			-	-6.2	-	Α	

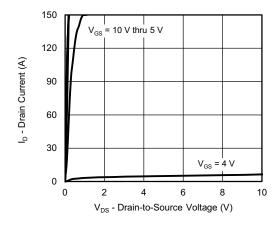
Notes

- a. Pulse test; pulse width $\leq 300~\mu s, \, duty \; cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing
- c. Independent of operating temperature

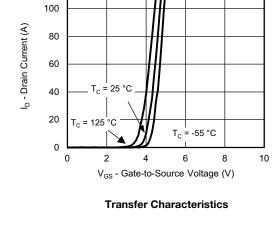
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



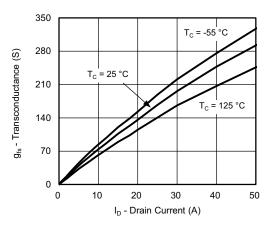
TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)



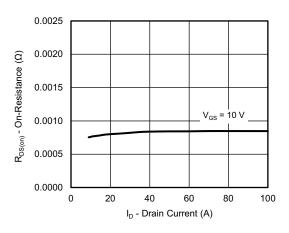
Output Characteristics



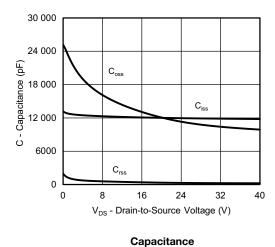
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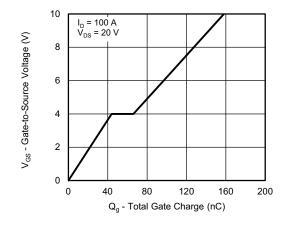


Transconductance



On-Resistance vs. Drain Current

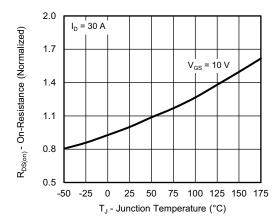




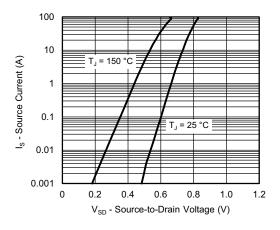
Gate Charge



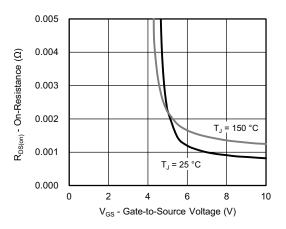
TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)



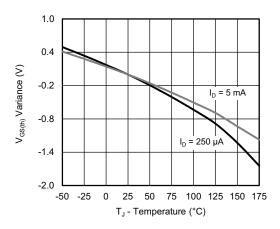
On-Resistance vs. Junction Temperature



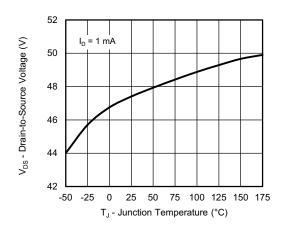
Source Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage



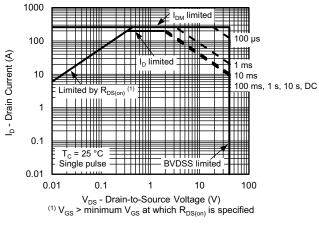
Threshold Voltage



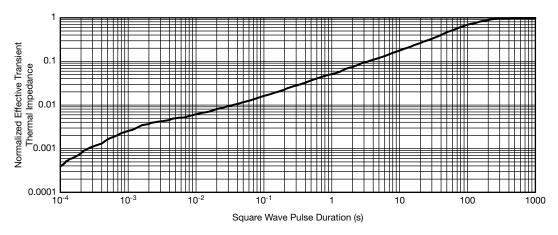
Drain Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_A = 25$ °C, unless otherwise noted)



Safe Operating Area



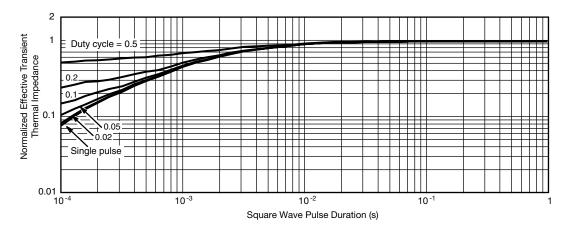
Normalized Thermal Transient Impedance, Junction-to-Ambient

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THERMAL RATINGS (T_A = 25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

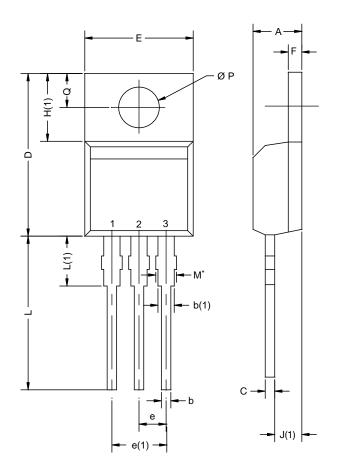
Note

- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)
 - Normalized Transient Thermal Impedance Junction-to-Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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